TOSHIBA Multichip Discrete Device

HN7G02FE

Power Management Switch Applications, Inverter Circuit Applications, Driver Circuit Applications and Interface Circuit Applications

Q1 (transistor): RN2110 equivalent Q2 (MOSFET): SSM3K03FE equivalent

Q1 (Transistor) Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	-50	V
Collector-emitter voltage	V _{CEO}	-50	V
Emitter-base voltage	V _{EBO}	-5	V
Collector current	IC	-100	mA

Q2 (MOSFET) Maximum Ratings (Ta = 25°C)

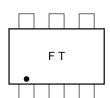
Characteristic	Symbol	Rating	Unit
Drain-source voltage	V_{DS}	20	V
Gate-source voltage	V _{GSS}	10	V
DC drain current	I _D	50	mA

Q1, Q2 Common Ratings (Ta = 25°C)

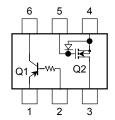
Characteristic	Symbol	Rating	Unit
Power dissipation	P (Note)	100	mW
Junction temperature	Tj	150	°C
Storage temperature range	T _{stg}	-55~150	°C

Note: Total rating

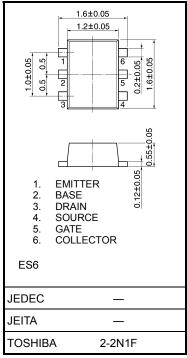
Marking



Equivalent Circuit (top view)



Unit: mm



Weight: 0.003g (typ.)

Q1 (Transistor) Electrical Characteristics (Ta = 25°C)

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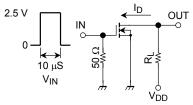
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cutoff current	I _{CBO}	$V_{CB} = -50 \text{ V}, I_E = 0$	_	_	-100	nA
Emitter cutoff current	I _{EBO}	$V_{EB} = -5 \text{ V}, I_C = 0$	_	_	-100	nA
DC current gain	h _{FE}	$V_{CE} = -5 \text{ V}, I_{C} = -1 \text{ mA}$	120	_	400	
Collector-emitter saturation voltage	V _{CE (sat)}	$I_C = -5 \text{ mA}, I_B = -0.25 \text{ mA}$	_	-0.1	-0.3	V
Input resistor	R1	_	3.29	4.7	6.11	kΩ

Q2 (MOSFET) Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage curr	ent	I _{GSS}	$V_{GS} = 10 \text{ V}, V_{DS} = 0$	_	_	1	μΑ
Drain-source brea	kdown voltage	V (BR) DSS	$I_D = 100 \ \mu A, \ V_{GS} = 0$	20	_	_	V
Drain cutoff currer	nt	I _{DSS}	$V_{DS} = 20 \ V, \ V_{GS} = 0$	_	_	1	μА
Gate threshold vo	Itage	V _{th}	$V_{DS} = 3 \text{ V}, I_{D} = 0.1 \text{ mA}$	0.7	_	1.3	V
Forward transfer a	admittance	Y _{fs}	$V_{DS} = 3 \text{ V}, I_D = 10 \text{ mA}$	25	50	_	mS
Drain-source ON-	resistance	R _{DS} (ON)	$I_D=10$ mA, $V_{GS}=2.5$ V	_	4	12	Ω
Input capacitance		C _{iss}	$V_{DS} = 3 V$, $V_{GS} = 0$, $f = 1 MHz$	_	11.0	_	pF
Reverse transfer of	capacitance	C _{rss}	$V_{DS} = 3 V$, $V_{GS} = 0$, $f = 1 MHz$	_	3.3	_	pF
Output capacitance		C _{oss}	$V_{DS} = 3 V$, $V_{GS} = 0$, $f = 1 MHz$	_	9.3	_	pF
Switching time	Turn-on time	t _{on}	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0 \sim 2.5 \text{ V}$	_	0.16	_	6
	Turn-off time	t _{off}	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0~2.5 \text{ V}$	_	0.19	_	μS

Switching Time Test Circuit

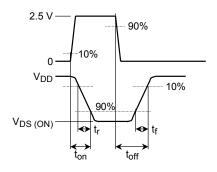
(a) Switching time test circuit



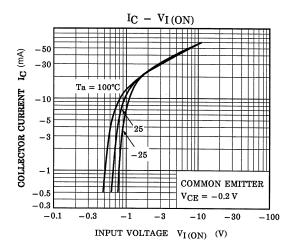
$$\begin{split} &V_{DD}=3 \text{ V} \\ &D.U. \leqq 1\% \\ &V_{IN}. \text{ } t_r, \text{ } t_f < 5 \text{ ns} \\ &(Z_{out}=50 \text{ }\Omega) \\ &Common \text{ source} \\ &Ta=25^{\circ}C \end{split}$$

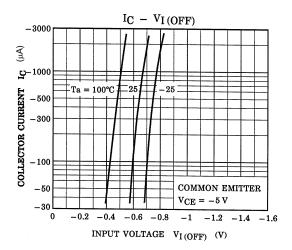
(b) V_{IN} V_{GS}

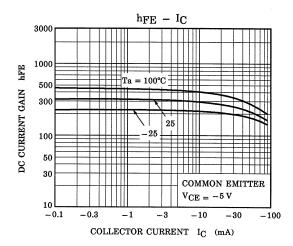
(c) V_{OUT}

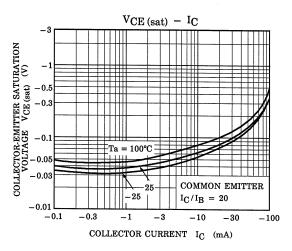


Q1 (Transistor)

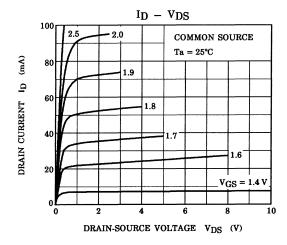


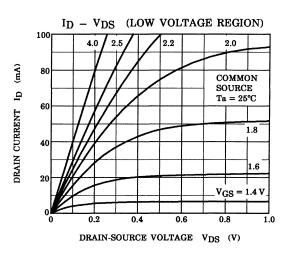


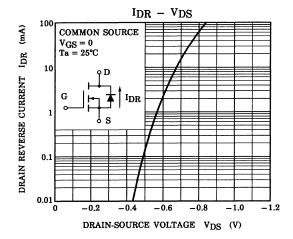


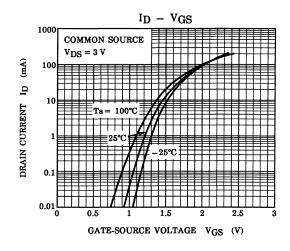


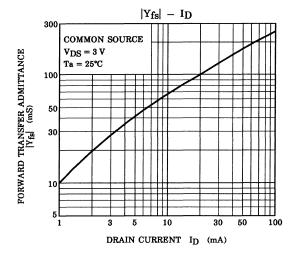
Q2 (MOSFET)

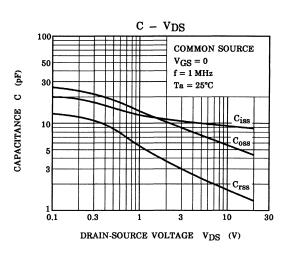




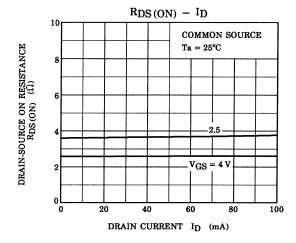


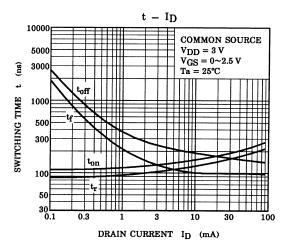


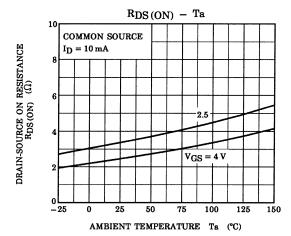




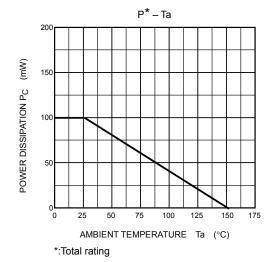
Q2 (MOSFET)







Q1, Q2 Common



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